



SHENZHEN LONG JING MICRO-ELECTRONICS CO., LTD.

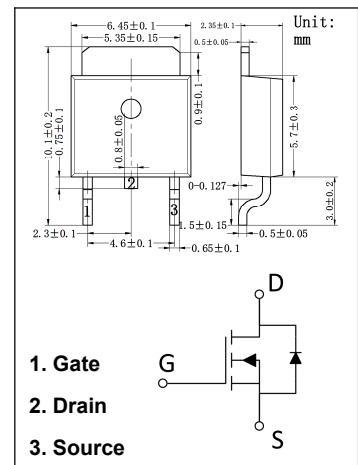
# TO-252 Plastic-Encapsulate MOSFETS

## D2N60D

100V N-Channel MOSFET

### Features

- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge : $Q_g = 6.8\text{nC}$  (Typ.)
- $B_{VDSS}=600\text{V}$ ,  $I_D=2\text{A}$
- $R_{DS(on)} : 4.5\Omega$  (Max) @ $V_G=10\text{V}$
- 100% Avalanche Tested



### Maximum Ratings ( $T_a=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source voltage	600	V
$I_D$	Drain Current	$T_C = 25^\circ\text{C}$	2
		$T_C = 100^\circ\text{C}$	1.25
$V_{GS(th)}$	Gate-Threshold Voltage	$\pm 30$	V
$I_{AR}$	Avalanche Current <sup>2)</sup>	2	A
$E_{AS}$	Single Pulse Avalanche Energy <sup>1)</sup>	120	mJ
$P_D$	Maximum Power Dissipation	44	W
$T_J$	Junction Temperature(MAX)	150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purpose, 1/8"from case for 5 seconds	300	$^\circ\text{C}$
$R_{\theta JA}$	Maximum Junction-to-Ambient	110	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Maximum Junction-to-Case (Drain)	2.87	$^\circ\text{C}/\text{W}$

## Electrical Characteristics ( $T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	600			V
$V_{GS(\text{th})}$	Gate-Threshold Voltage <sup>3)</sup>	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2		4	V
$I_{GSS}$	Gate-body Leakage current	$V_{DS}=0\text{ V}, V_{GS}=\pm 30\text{ V}$			$\pm 100$	nA
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
$R_{DS(\text{on})}$	Drain-Source On-Resistance <sup>3)</sup>	$V_{GS}=10\text{V}, I_D = 1\text{A}$			4.5	$\Omega$
$C_{iss}$	Input Capacitance <sup>4)</sup>	$V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$		298		pF
$C_{oss}$	Output Capacitance <sup>4)</sup>			40		
$C_{rss}$	Reverse Transfer Capacitance <sup>4)</sup>			5		
$Q_g$	Total Gate Charge <sup>4)</sup>	$V_{GS} = 10\text{ V},$ $I_D = 2\text{ A},$ $V_{DS} = 480\text{ V}$		6.8		nC
$Q_{gs}$	Gate-Source Charge <sup>4)</sup>			2.0		
$Q_{gd}$	Gate-Drain Charge <sup>4)</sup>			1.8		
$t_{d(on)}$	Turn-On Delay Time <sup>4)</sup>	$V_{DD} = 300\text{ V}, I_D=2\text{A}$ $R_G = 25\Omega$		10	30	ns
$t_r$	Rise Time <sup>4)</sup>			24	60	
$t_{d(off)}$	Turn-Off Delay Time <sup>4)</sup>			20	50	
$t_f$	Fall Time <sup>4)</sup>			25	60	
$I_s$	Continuous Source-Drain Diode Current	<sup>2)</sup>			2	A
$V_{SD}$	Diode Forward Voltage <sup>3)</sup>	$I_S = 10\text{A}, V_{GS} = 0\text{V}$			1.5	V
$t_{rr}$	Body Diode Reverse Recovery Time	$T_J = 25^\circ\text{C}, I_S = 2\text{ A},$ $dI/dt = 100\text{ A}/\mu\text{s}$		380		nS
$Q_{rr}$	Body Diode Reverse Recovery Charge			0.9		
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$ )				

### Notes

1.Repetitive Rating: Pulse width limited by maximum junction temperature..

2.Surface Mounted on FR4 Board,  $t \leq 10$  sec.

3.Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .

4.Guaranteed by design, not subject to production

## Typical Characteristics

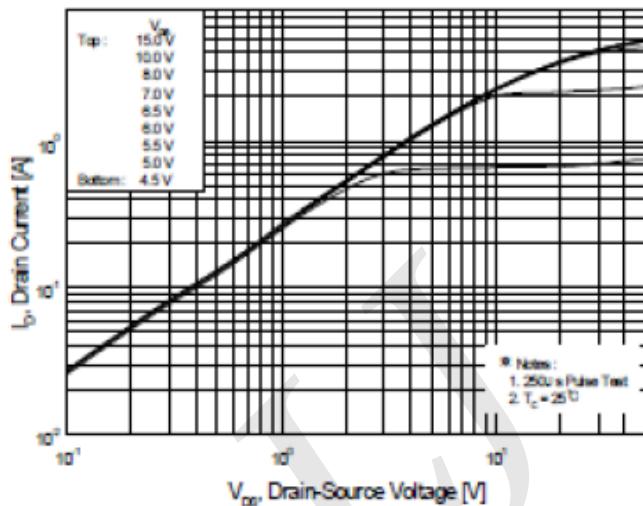


Figure 1. On-Region Characteristics

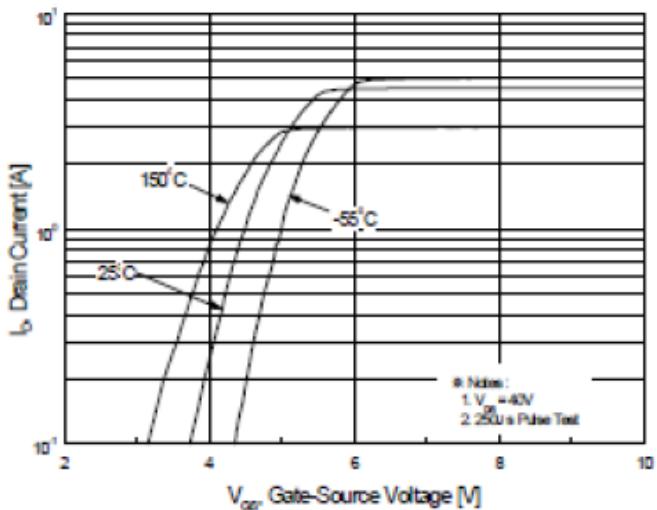


Figure 2. Transfer Characteristics

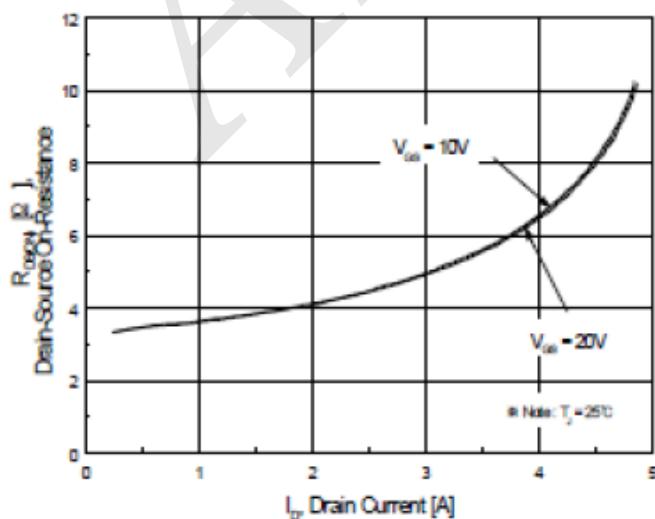


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

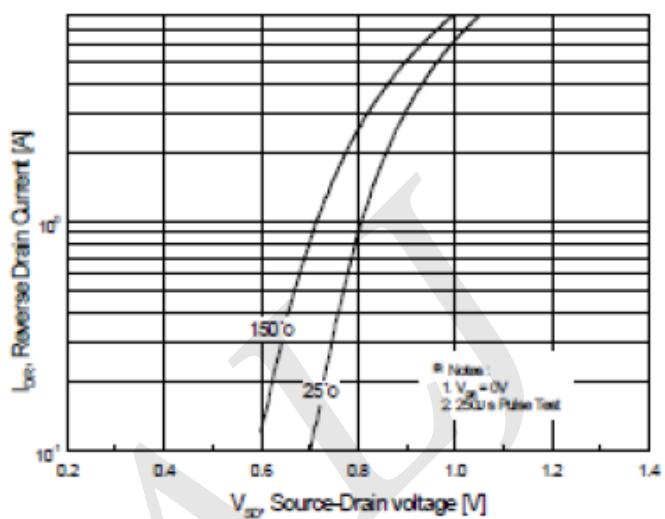


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

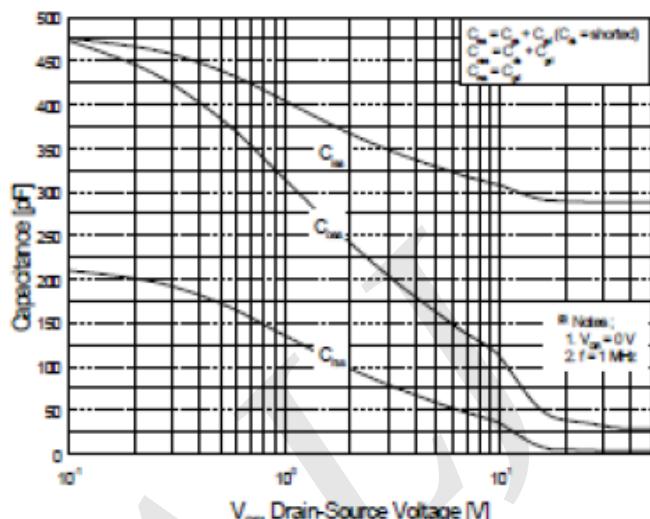


Figure 5. Capacitance Characteristics

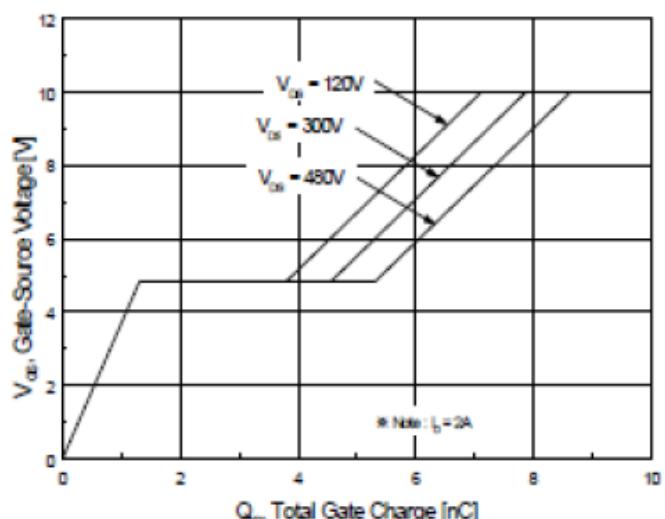


Figure 6. Gate Charge Characteristics

## Typical Characteristics (Cont.)

